SHEET 1 OF 1

Form PTO 1449		U.S. DEPARTMENT (F COMMERCE	ATTY DOCKET NO.		SERIAL NO. 10/584,052			
(Modified)		PATENT AND TRAD	EMARK OFFICE	292873US0PCT					
				APPLICANT					
LIST OF	REFER	ENCES CITED BY API	PLICANT	Stephane POCAS, et al.					
				FILING DATE		GROUP			
				June 22, 2006		2892			
U.S. PATENT DOCUMENTS									
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS			
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OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)									
/E.J./	AW	Hartmut BRACHT, "DIFFUSION MECHANISMS AND INTRINSIC POINT-DEFECT PROPERTIES IN SILICON", www.mrs.org/publications/bulletin, MRS Bulletin/June 2000, pages 22-27.							
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	AZ			Additional References sheet(s) attached					
Examiner						Date Considered 11/10/2009			
*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.									